


Issue Classification 	Application/Control No. 10/587,340	Applicant(s)/Patent under Reexamination HATTORI ET AL.
	Examiner Jaydi A. San Martin	Art Unit 2834

ISSUE CLASSIFICATION														
ORIGINAL					INTERNATIONAL CLASSIFICATION									
CLASS		SUBCLASS			CLAIMED						NON-CLAIMED			
310		800			H	01	L	41	/09					/
CROSS REFERENCES					H	02	N	11	/00					/
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)													
310	339								/					/
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----- (Assistant Examiner) (Date)		/J. San Martin/ J. San Martin		Total Claims Allowed: 11	
(Legal Instruments Examiner) (Date)		(Primary Examiner) (Date)		O.G. Print Claim(s) 1	
				O.G. Print Fig. 6	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant														<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original			
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Search Notes

Application/Control No.

10/587,340

Examiner

Jaydi A. San Martin

Applicant(s)/Patent under
Reexamination

HATTORI ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	311,358, 339	9/23/2007	JSM
310	800	1/31/2008	JSM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see	report	1/31/2008	JSM

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IEEE NPL search	1/31/2008	JSM